Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/667,372	TAKAHASHI, TOSHIHIDE
Examiner	Art Unit
Anabel M. Ton	2875

	SEAR	CHED	
Class	Subclass	Date	Examiner
362	546,549	2/15/2005	AT

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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